

**Workshop 1:**  
Electron Beam Size Measurements, April 24  
Program

Each presentation to be 20 minutes plus 5 minutes discussion

8.45 am	Welcome and Introduction	Victor Suller (CAMD)
9.00 am	Overview of Beam Size Measurements	Jeff Corbett (SPEAR)
9.25 am	Beam size measurements at CAMD	Victor Suller (CAMD)
9.50 am	Beam Size Measurements at the Canadian LS	Les Dallin (CLS)
10.15 am	Coffee Break	
10.45 am	Software for Pinhole Camera Simulation	Jeff Corbett (SPEAR)
11.10 am	New Crystal Collimator for Source Size Measurements	Jeff White (CHESS)
11.35 am	Discussion	
12.00 pm	Concluding remarks	Victor Suller (CAMD)

Free lunch is provided.